

Measurement of transverse Emittance



The emittance characterizes the whole beam quality, assuming linear behavior as described by second order differential equation.

It is defined within the phase space as: $\varepsilon_x = \frac{1}{\pi} \int_A dx dx'$

The measurement is based on determination of:

either profile width σ_x and angular width σ_x' at one location
or σ_x at different locations and linear transformations.

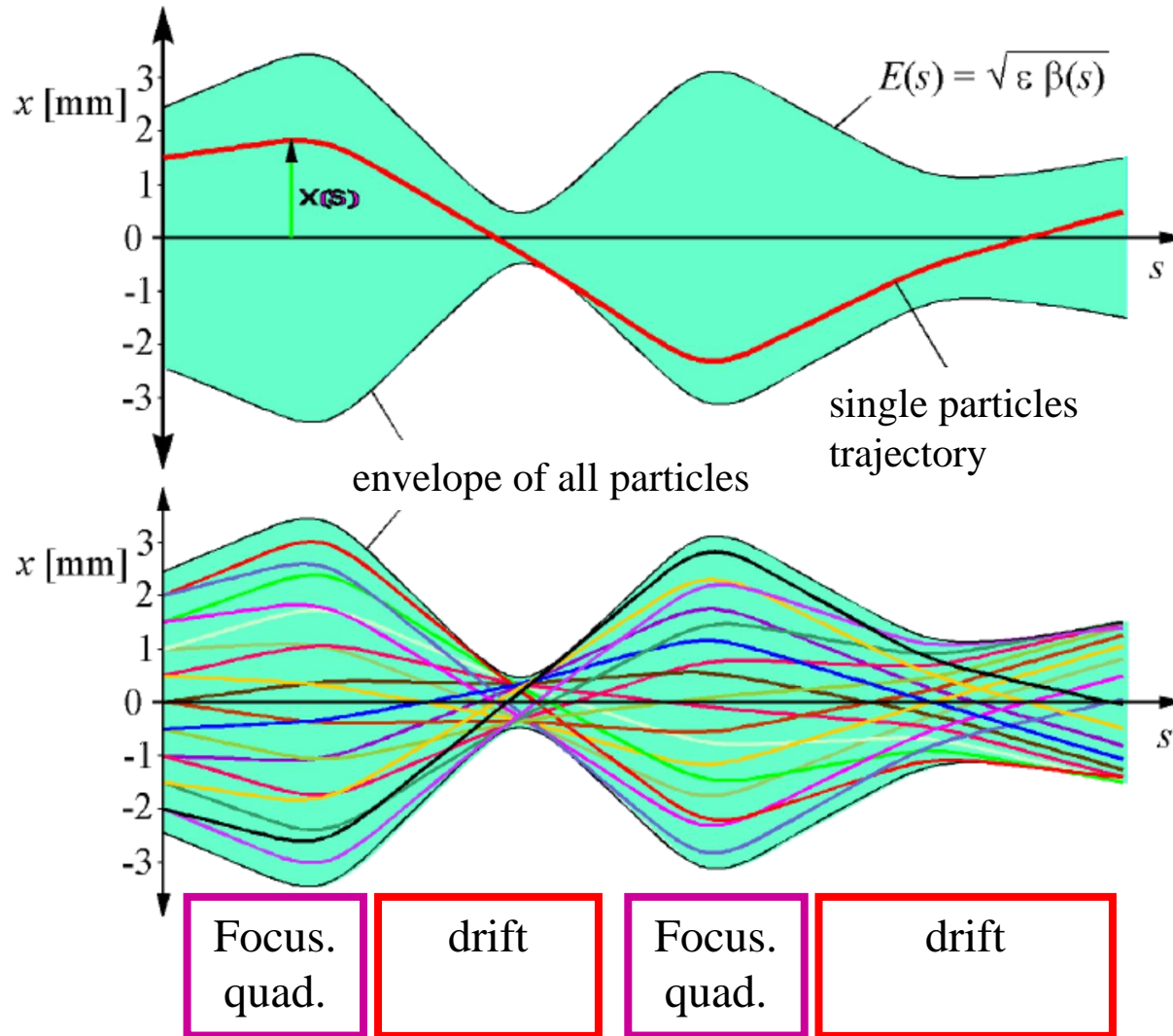
Different devices are used at transfer lines:

- Lower energies $E_{kin} < 100$ MeV/u: slit-grid device, pepper-pot (suited in case of non-linear forces).
- All beams: Quadrupole variation, 'three grid' method using linear transformations (**not** well suited in the presence of non-linear forces)

Synchrotron: lattice functions results in stability criterion

⇒ beam width delivers emittance: $\varepsilon_x = \frac{1}{\beta_x(s)} \left[\sigma_x^2 - \left(D(s) \frac{\Delta p}{p} \right) \right]$ and $\varepsilon_y = \frac{\sigma_y^2}{\beta_y(s)}$

Excuse: Particle Trajectory and Characterization of many Particles



- Single particle trajectories are forming a beam
- They have a distribution of start positions and angles
- ⇒ Characteristic quantity is the **beam envelope**
- **Goal:** Transformation of envelope Behavior of whole ensemble

Plot: Wille



Definition of transverse Emittance

The emittance characterizes the whole beam quality: $\epsilon_x = \frac{1}{\pi} \int_A dx dx'$

Ansatz:

Beam matrix at one location: $\sigma = \begin{pmatrix} \sigma_{11} & \sigma_{12} \\ \sigma_{12} & \sigma_{22} \end{pmatrix} = \epsilon \cdot \begin{pmatrix} \beta & -\alpha \\ -\alpha & \gamma \end{pmatrix}$ with $\vec{x} = \begin{pmatrix} x \\ x' \end{pmatrix}$

It describes a 2-dim probability distr.

The value of emittance is:

$$\epsilon_x = \sqrt{\det \sigma} = \sqrt{\sigma_{11}\sigma_{22} - \sigma_{12}^2}$$

For the profile and angular measurement:

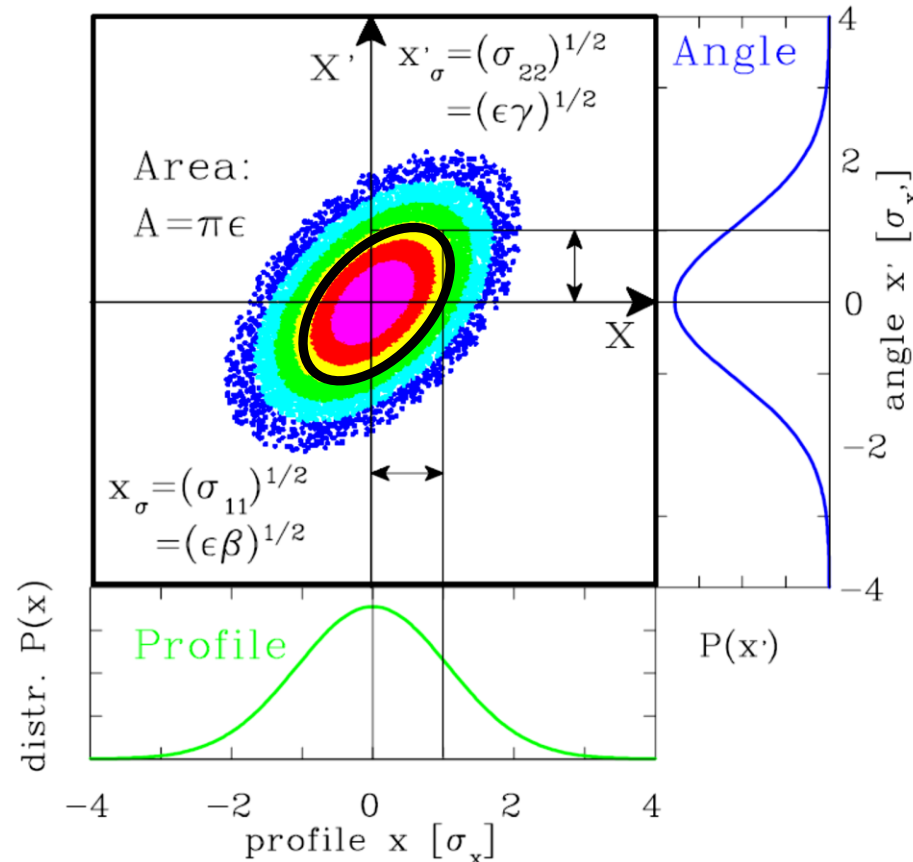
$$x_\sigma = \sqrt{\sigma_{11}} = \sqrt{\epsilon\beta} \quad \text{and}$$

$$x'_\sigma = \sqrt{\sigma_{22}} = \sqrt{\epsilon\gamma}$$

Geometrical interpretation:

All points \mathbf{x} fulfilling $\mathbf{x}^t \cdot \sigma^{-1} \cdot \mathbf{x} = 1$ are located on a **ellipse**

$$\sigma_{22}x^2 - 2\sigma_{12}xx' + \sigma_{11}x'^2 = \det \sigma = \epsilon_x^2$$



The Emittance for Gaussian Beams



The density function for a 2-dim Gaussian distribution is:

$$\rho(x, x') = \frac{1}{2\pi\epsilon} \exp \left[-\frac{1}{2} \vec{x}^T \sigma^{-1} \vec{x} \right]$$

$$= \frac{1}{2\pi\epsilon} \exp \left[\frac{-1}{2 \det \sigma} (\sigma_{22}x^2 - 2\sigma_{12}xx' + \sigma_{11}x'^2) \right]$$

It describes an ellipse with the characteristics profile and angle Gaussian distribution of width

$$x_\sigma \equiv \sqrt{\langle x^2 \rangle} = \sqrt{\sigma_{11}} \quad \text{and}$$

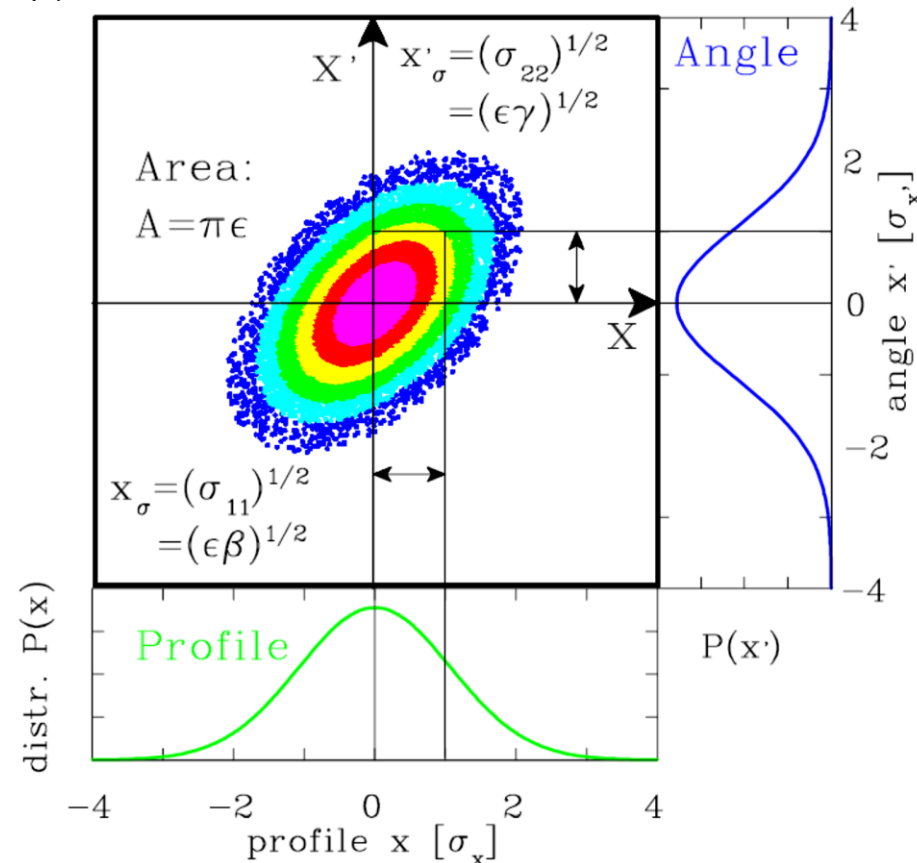
$$x'_\sigma \equiv \sqrt{\langle x'^2 \rangle} = \sqrt{\sigma_{22}}$$

and the correlation or covariance

$$\text{cov} \equiv \sqrt{\langle xx' \rangle} = \sqrt{\sigma_{12}}$$

For $\mathbf{A} = \begin{pmatrix} a & b \\ c & d \end{pmatrix}$ it is $\mathbf{A}^{-1} = \frac{1}{ad-bc} \begin{pmatrix} d & -b \\ -c & a \end{pmatrix}$

assuming $\det(\mathbf{A}) = ad-bc \neq 0 \Leftrightarrow$ matrix invertible



The Emittance for Gaussian and non-Gaussian Beams



The beam distribution can be non-Gaussian, e.g. at:

- beams behind ion source
- space charged dominated beams at LINAC & synchrotron
- cooled beams in storage rings

General description of emittance

using terms of 2-dim distribution:

It describes the value for 1 stand. derivation

Covariance
i.e. correlation

Variances

$$\mathcal{E}_{rms} = \sqrt{\langle x^2 \rangle \langle x'^2 \rangle - \langle xx' \rangle^2}$$

For discrete distribution:

$$\langle x \rangle = \frac{\sum_{i,j} \rho(i,j) \cdot x_i x'_j}{\sum_{i,j} \rho(i,j)}$$

and correspondingly for all other moments

$$\langle x \rangle \equiv \mu = \frac{\iint x \cdot \rho(x, x') dx dx'}{\iint \rho(x, x') dx dx'}$$

$$\langle x' \rangle \equiv \mu' = \frac{\iint x' \cdot \rho(x, x') dx dx'}{\iint \rho(x, x') dx dx'}$$

$$\langle x^n \rangle = \frac{\iint (x - \mu)^n \cdot \rho(x, x') dx dx'}{\iint \rho(x, x') dx dx'}$$

$$\langle x'^n \rangle = \frac{\iint (x' - \mu')^n \cdot \rho(x, x') dx dx'}{\iint \rho(x, x') dx dx'}$$

$$\text{covariance : } \langle xx' \rangle = \frac{\iint (x - \mu)(x' - \mu') \cdot \rho(x, x') dx dx'}{\iint \rho(x, x') dx dx'}$$

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Covariance
i.e. correlation

General description of emittance
using terms of 2-dim distribution:

$$\mathcal{E}_{rms} = \sqrt{\underbrace{\langle x^2 \rangle \langle x'^2 \rangle}_{\text{Variances}} - \underbrace{\langle xx' \rangle^2}_{\text{Covariance}}}$$

It describes the value for 1 stand. derivation

For Gaussian beams only:

$\epsilon_{rms} \leftrightarrow$ interpreted as area containing a fraction f of ions: $\epsilon(f) = -2\pi\epsilon_{rms} \cdot \ln(1-f)$

factor to ϵ_{rms}	$1 \cdot \epsilon_{rms}$	$\pi \cdot \epsilon_{rms}$	$2\pi \cdot \epsilon_{rms}$	$4\pi \cdot \epsilon_{rms}$	$6\pi \cdot \epsilon_{rms}$	$8\pi \cdot \epsilon_{rms}$
faction of beam f [%]	15	39	63	86	95	98

Care: no common definition of emittance concerning the fraction f



Outline:

- Definition and some properties of transverse **emittance**
- **Slit-Grid device: scanning method**
scanning slit → beam position & grid → angular distribution
- **Pepper-pot device: single shot device**
- **Quadrupole strength variation and position measurement**
- **Summary**

The Slit-Grid Measurement Device

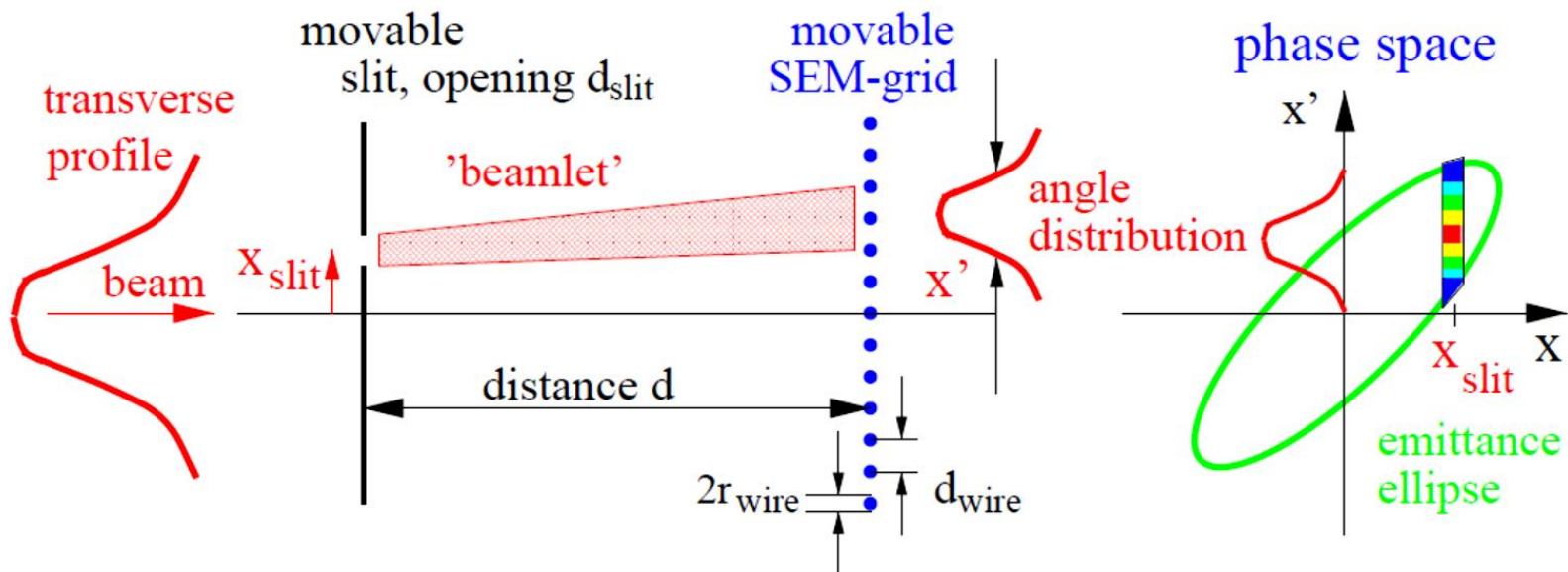


Slit-Grid: Direct determination of position and angle distribution.

Used for protons/heavy ions with $E_{kin} < 100 \text{ MeV/u} \Rightarrow \text{range } R < 1 \text{ cm}$.

Hardware

Analysis



Slit: position $P(x)$ with typical width: 0.1 to 0.5 mm

Distance: 10 cm to 1 m (depending on beam velocity)

SEM-Grid: angle distribution $P(x')$

Slit & SEM-Grid

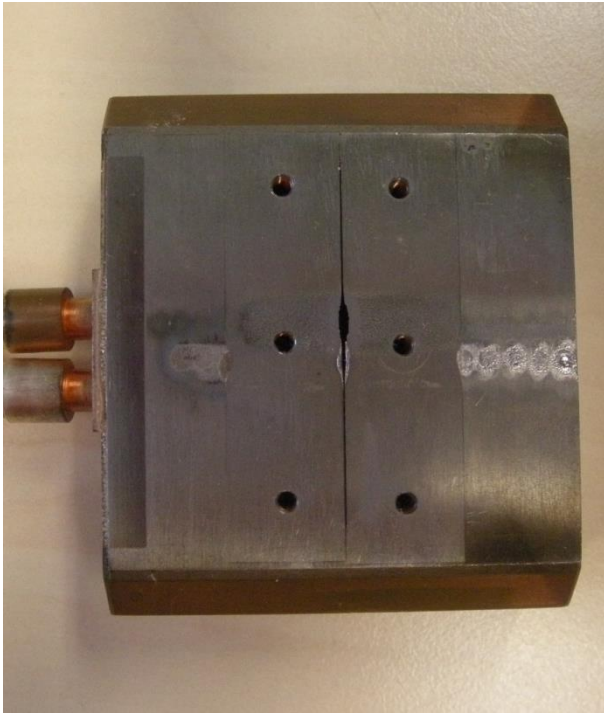


Slit with e.g. 0.1 mm thickness

→ Transmission only from Δx .

Example: Slit of width 0.1 mm (defect)

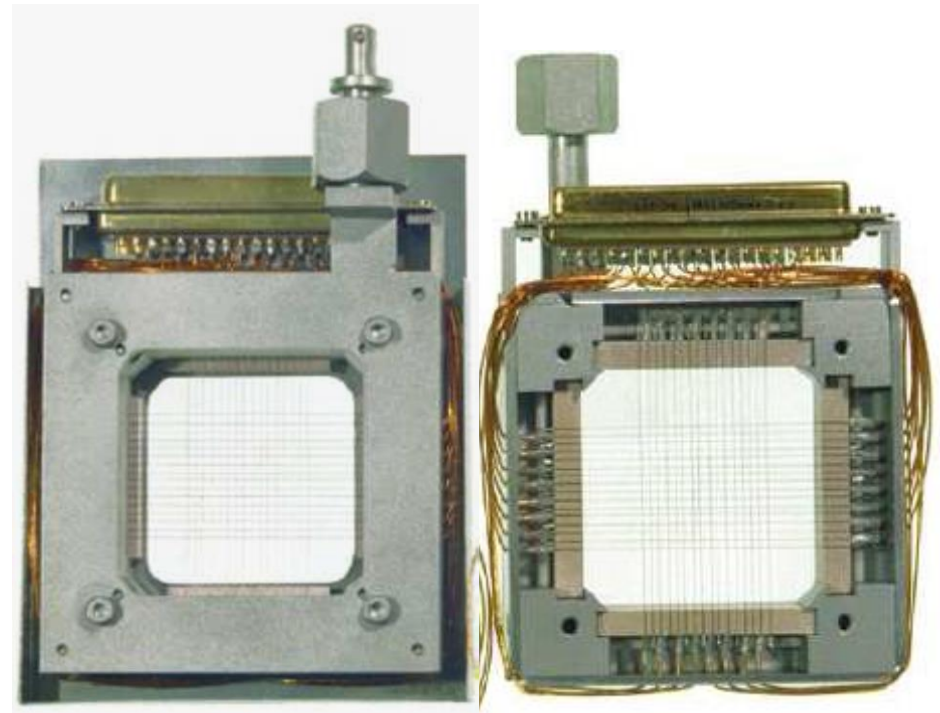
Moved by stepping motor, 0.1 mm resolution



Beam surface interaction: e^- emission

→ measurement of current.

Example: 15 wire spaced by 1.5 mm:



Each wire is equipped with one I/U converter
different ranges settings by R_i

→ very large dynamic range up to 10^6 .

Display of Measurement Results



The distribution of the ions is depicted as a function of

- Position [mm]
- Angle [mrad]

The distribution can be visualized by

- Mountain plot
- Contour plot

Calc. of 2nd moments $\langle x^2 \rangle$, $\langle x'^2 \rangle$ & $\langle xx' \rangle$

Emittance value ε_{rms} from

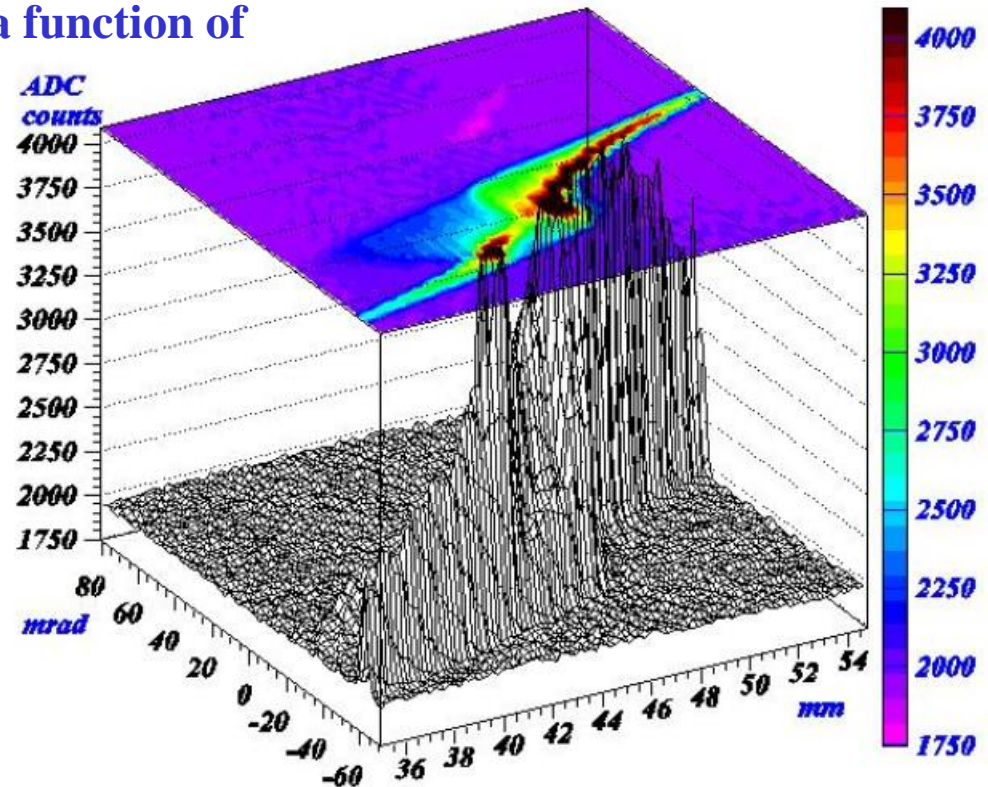
$$\varepsilon_{rms} = \sqrt{\langle x^2 \rangle \langle x'^2 \rangle - \langle xx' \rangle^2}$$

⇒ Problems:

- Finite **binning** results in limited resolution
- **Background** → large influence on $\langle x^2 \rangle$, $\langle x'^2 \rangle$ and $\langle xx' \rangle$

Or fit of distribution i.e. ellipse to data

⇒ Effective emittance only



Beam: Ar⁴⁺, 60 KeV, 15 μA
at Spiral2 Phoenix ECR source.
Plot from P. Ausset, DIPAC 2009

The Resolution of a Slit-Grid Device



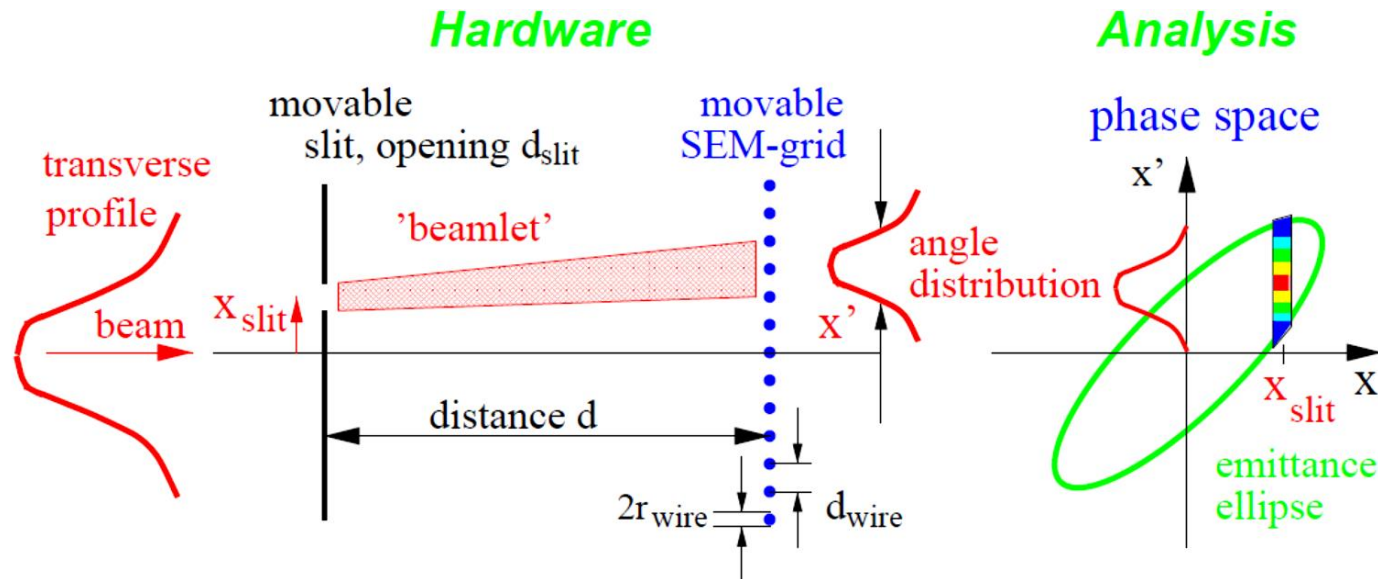
The width of the slit d_{slit} gives the resolution in space $\Delta x = d_{slit}$.

The angle resolution is $\Delta x' = (d_{wire} + 2r_{wire})/d$

⇒ discretization element $\Delta x \cdot \Delta x'$.

By scanning the SEM-grid the angle resolution can be improved.

Problems for small beam sizes or parallel beams.



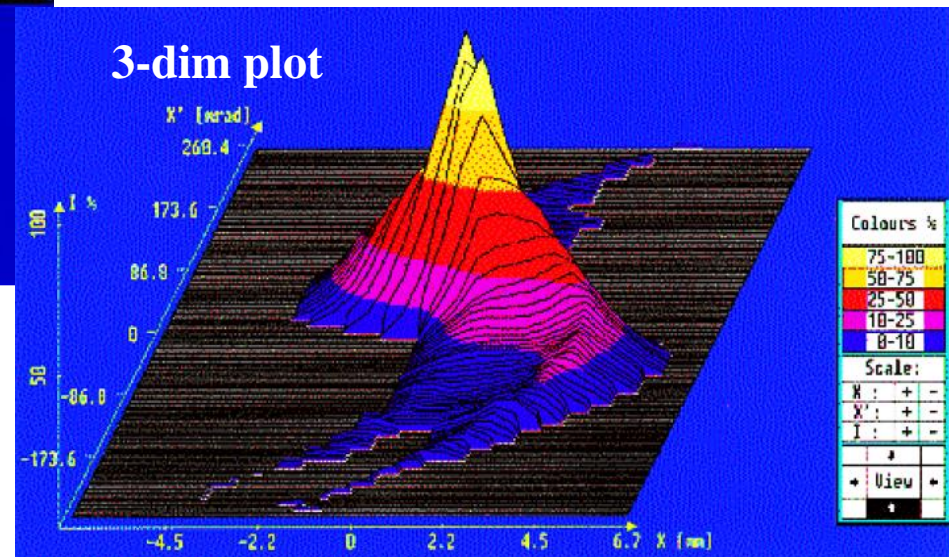
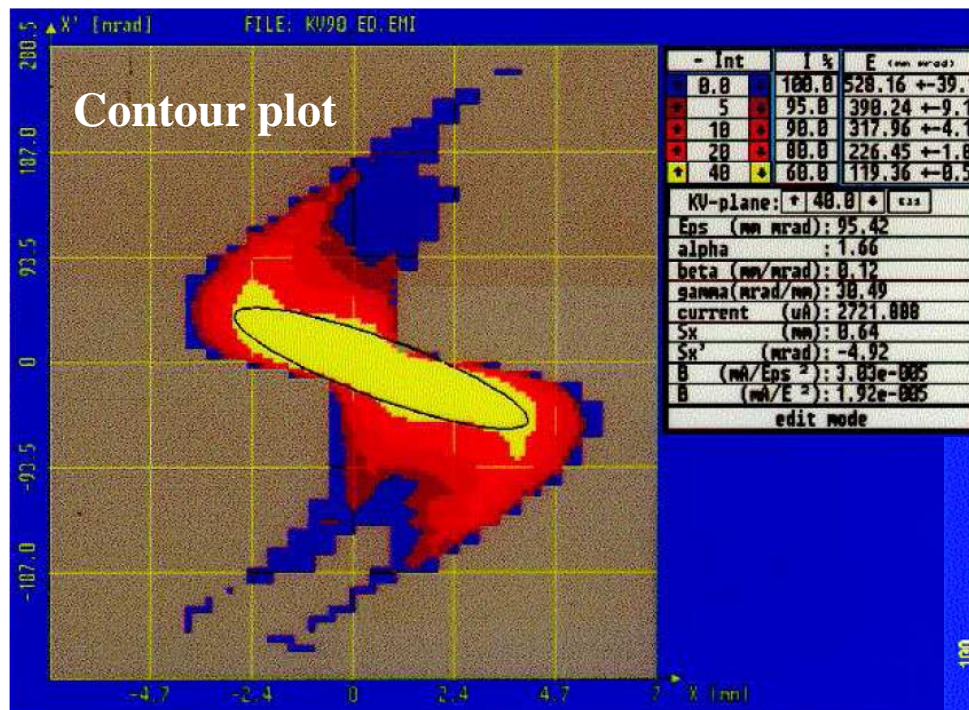
For pulsed LINACs: Only one measurement each pulse → long measuring time required.

Result of an Slit-Grid Emittance Measurement



Result for a beam behind ion source: ➤ here aberration in quadrupoles due to large beam size

- different evaluation and plots possible
- can monitor any distribution



Low energy ion beam:

→ well suited for emittance showing space-charge effects or aberrations.



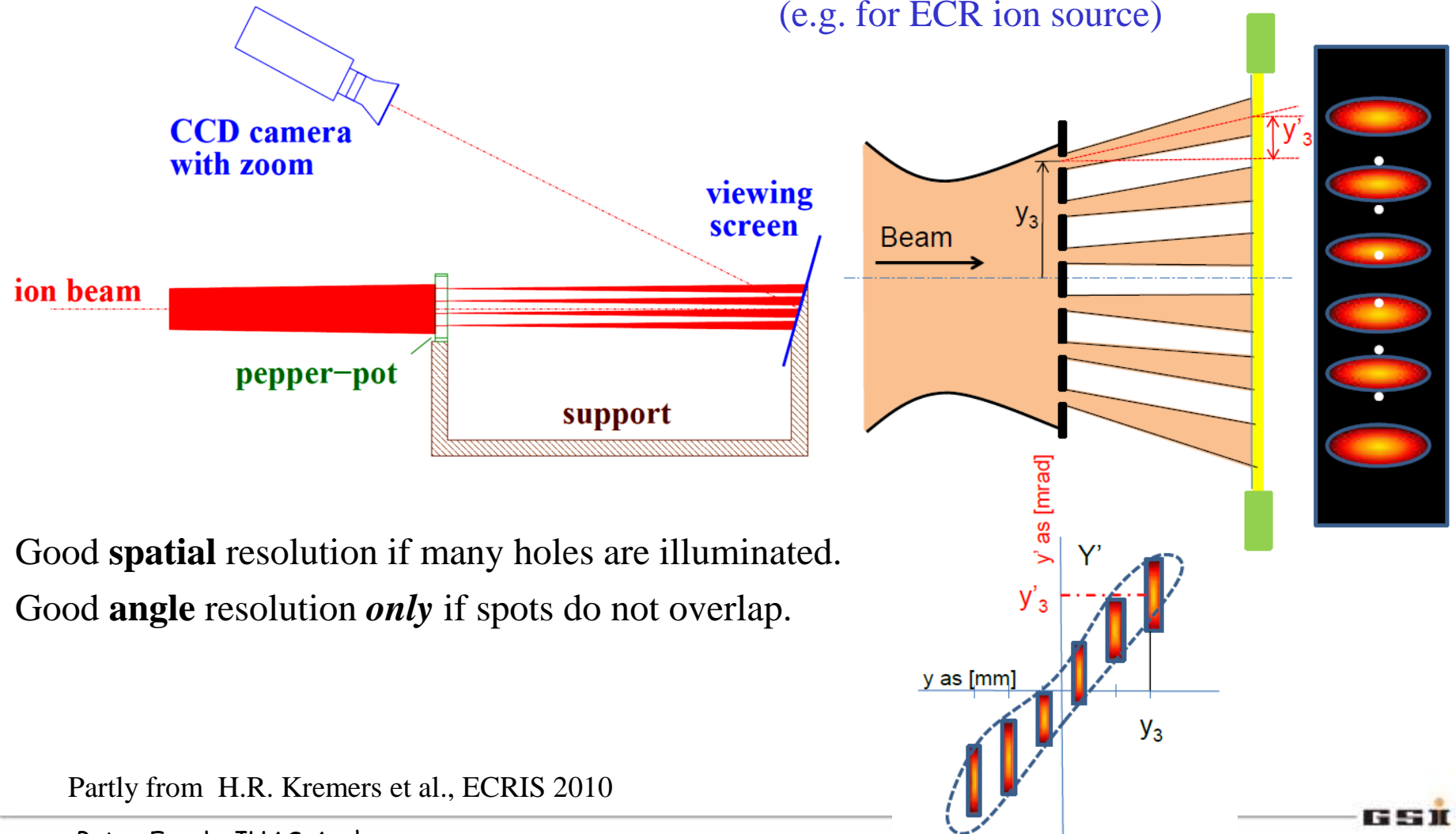
Outline:

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hole-plate → beam position & screen → angular distribution
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The Pepperpot Emittance Device



- For pulsed LINAC: Measurement within one pulse is an advantage
- If horizontal and vertical direction coupled → 2-dim evaluation **required** (e.g. for ECR ion source)



Good **spatial** resolution if many holes are illuminated.
 Good **angle** resolution *only* if spots do not overlap.

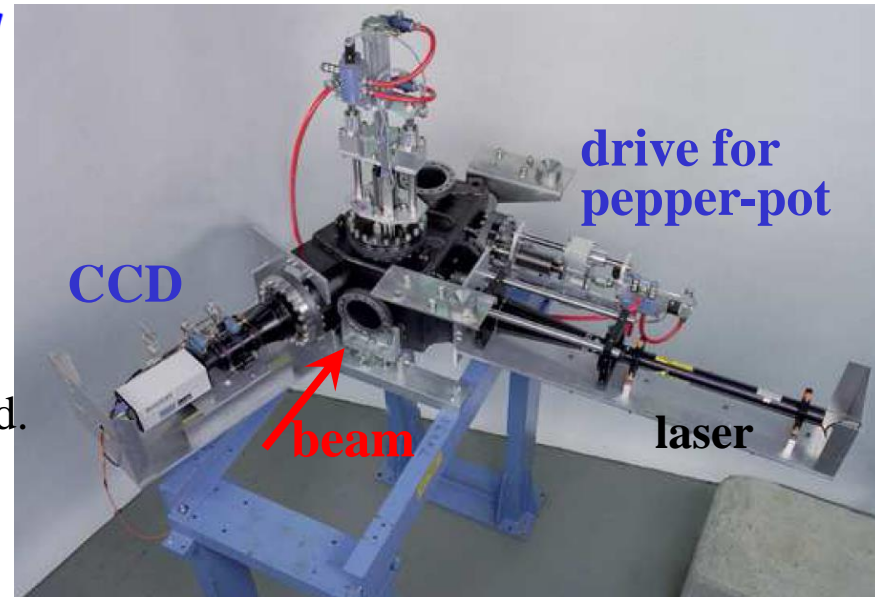
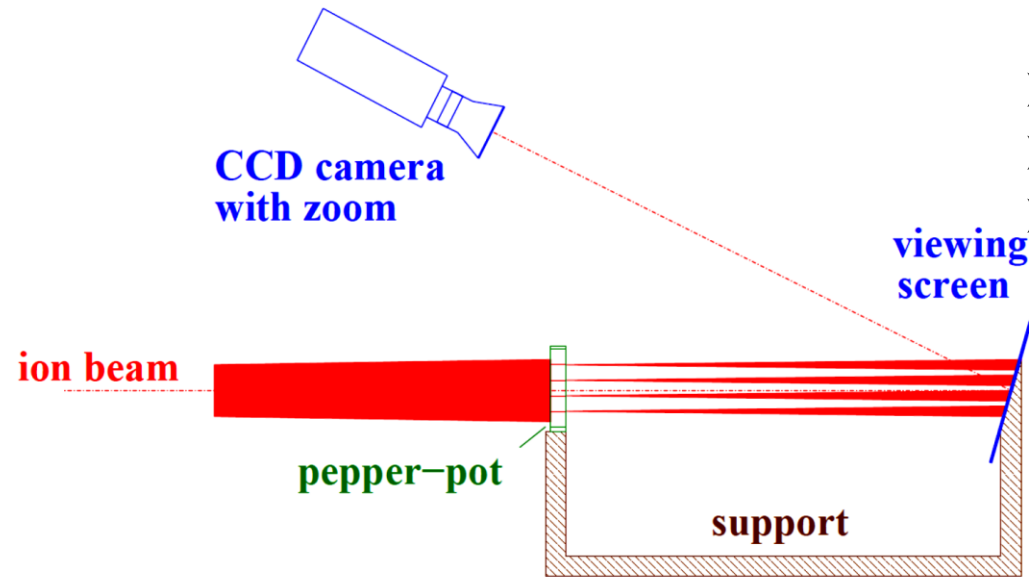
Partly from H.R. Kremers et al., ECRIS 2010

The Pepperpot Emittance Device at GSI UNILAC



Example GSI-LINAC 0.12 to 11 MeV/u:

- *Pepper-pot*: 15×15 holes with $\varnothing 0.1\text{mm}$ on a $50 \times 50\text{ mm}^2$ copper plate
- *Distance*: pepper-pot-screen: 25 cm
- *Screen*: Al_2O_3 , $\varnothing 50\text{ mm}$
- *Data acquisition*: high resolution CCD

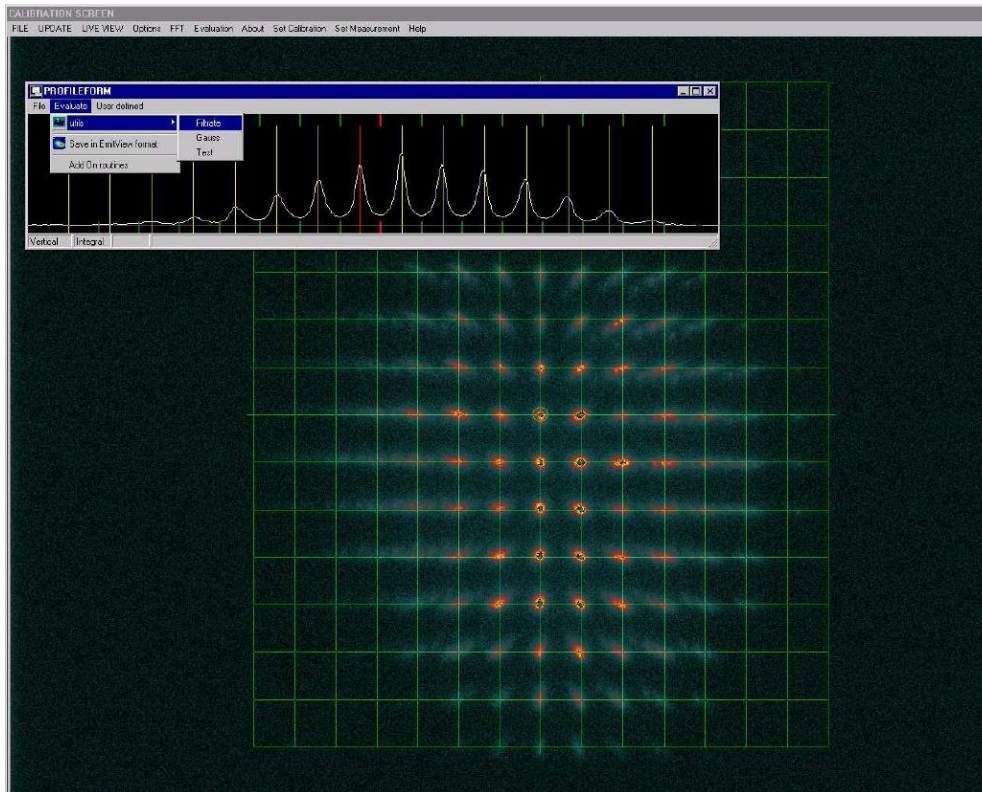


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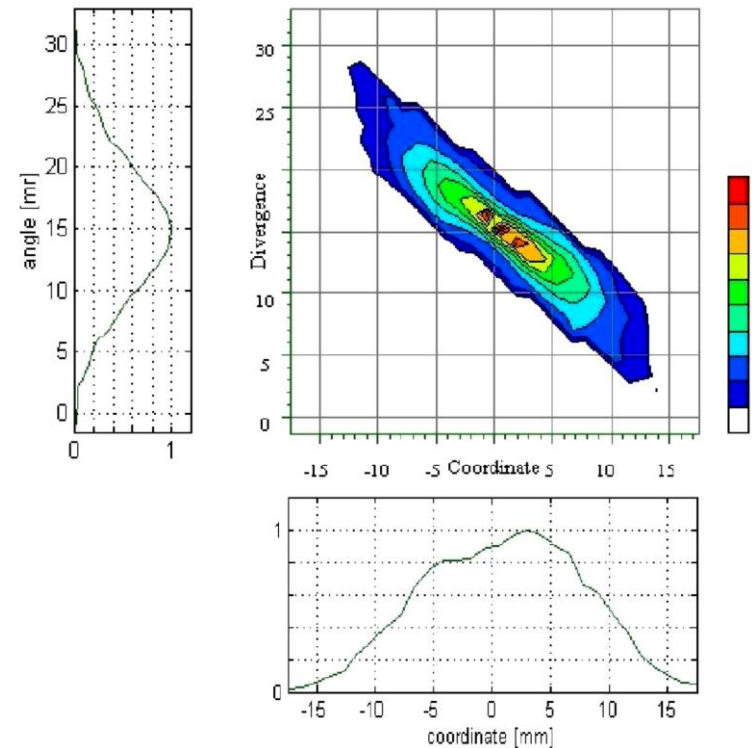
Result of a Pepperpot Emittance Measurement



Example: Ar¹⁺ ion beam at 1.4 MeV/u,
screen image from single shot at GSI:



Data analysis:
Projection on
horizontal and vertical plane
→ analog to slit-grid.

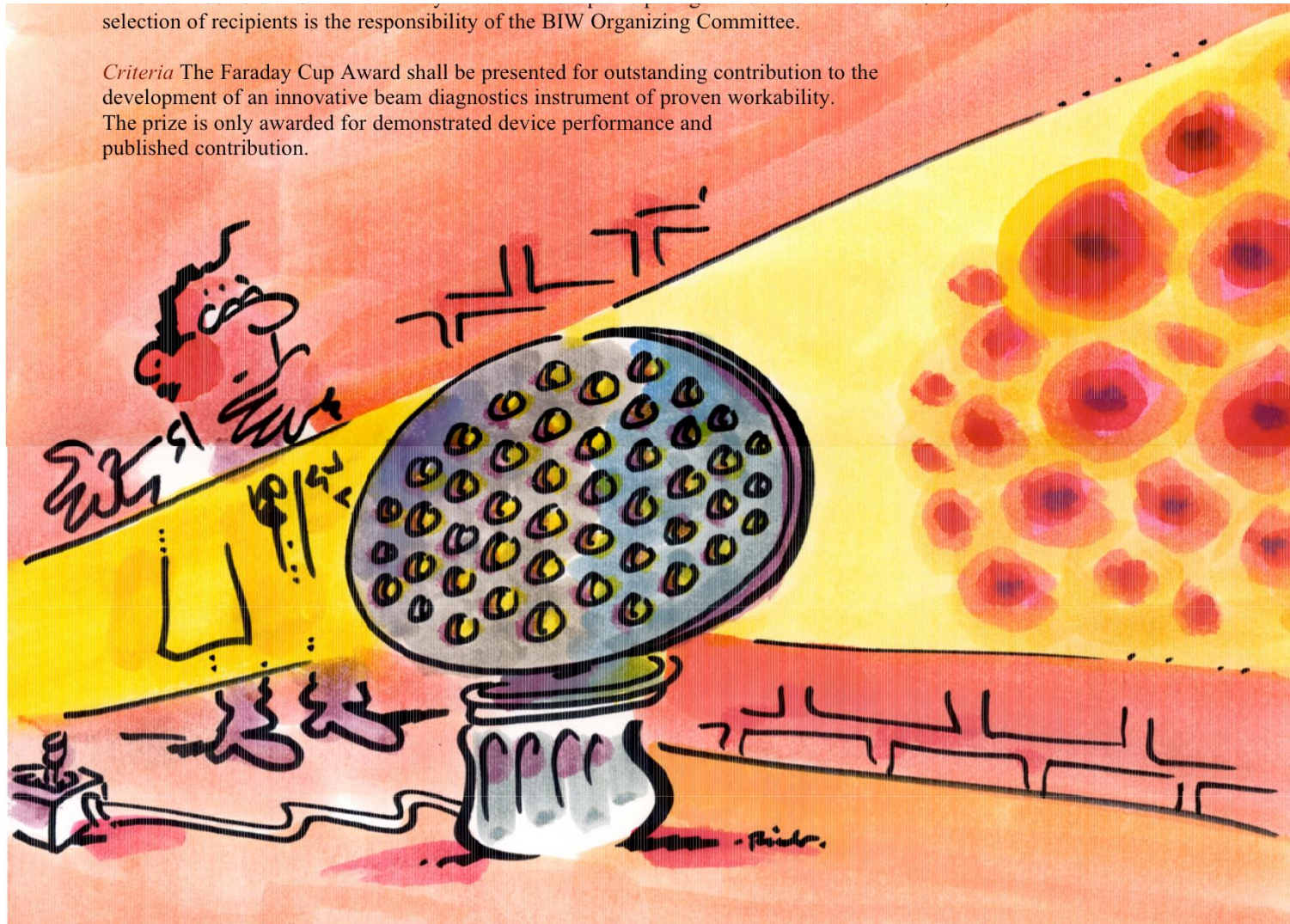


The Artist View of a Pepperpot Emittance Device



selection of recipients is the responsibility of the BIW Organizing Committee.

Criteria The Faraday Cup Award shall be presented for outstanding contribution to the development of an innovative beam diagnostics instrument of proven workability. The prize is only awarded for demonstrated device performance and published contribution.

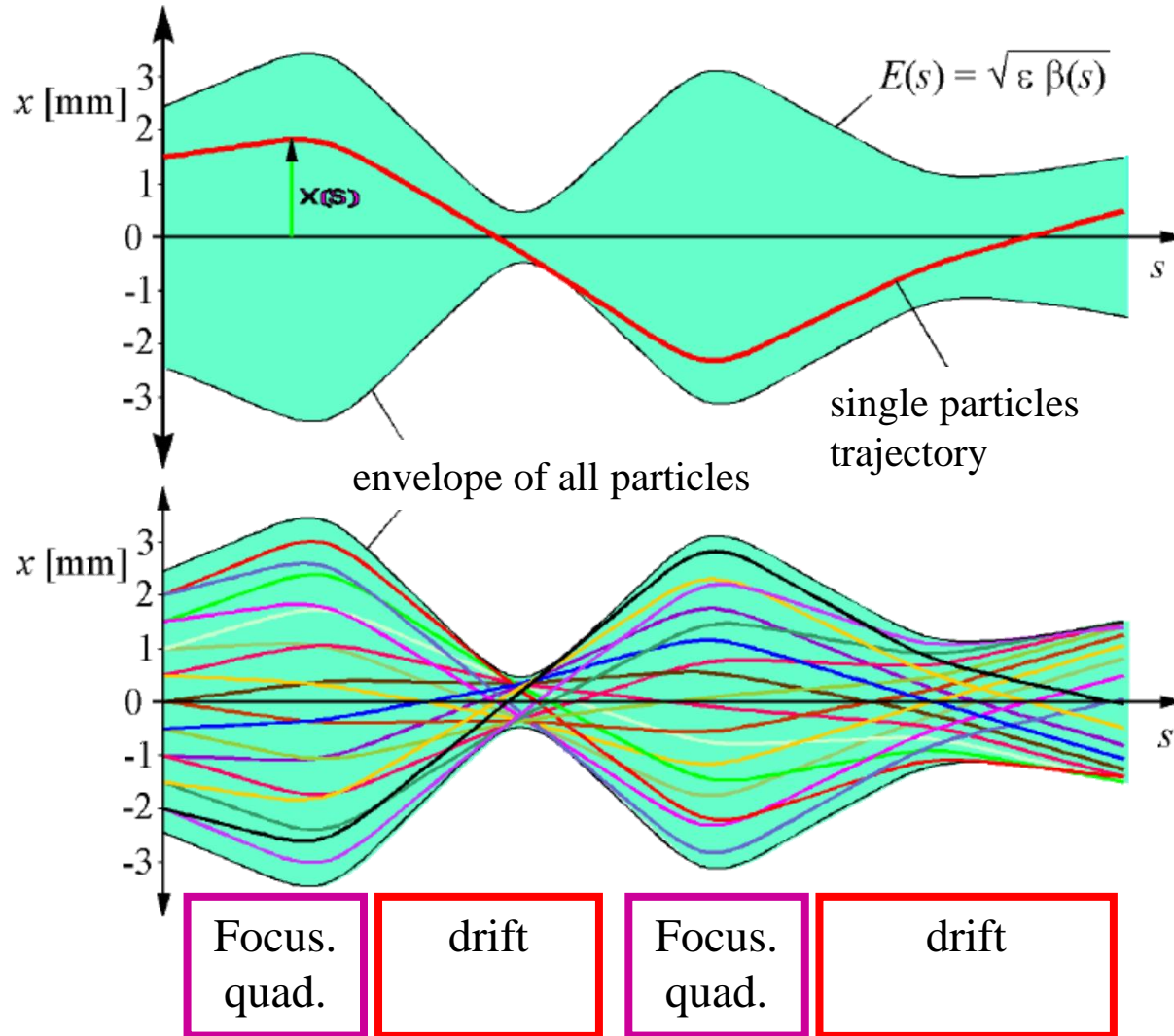




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- Pepper-pot device: single shot device
hole-plate → beam position & screen → angular distribution
- **Quadrupole strength variation and position measurement**
emittance from several profile measurement and beam optical calculation
- **Summary**

Excuse: Particle Trajectory and Characterization of many Particles



- Single particle trajectories are forming a beam
- They have a distribution of start positions and angles
- ⇒ Characteristic quantity is the **beam envelope**
- **Goal:** Transformation of envelope Behavior of whole ensemble

Plot: Wille

Excuse: Definition of Offset and Divergence

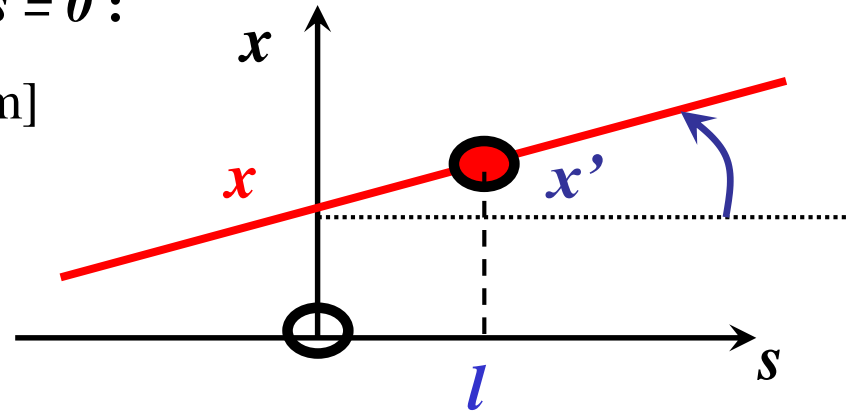


Horizontal and vertical coordinates at $s = 0$:

➤ x : Offset from reference orbit in [mm]

➤ x' : Angle of trajectory in unit [mrad]

$$x' = dx / ds$$



Assumption: par-axial beams:

➤ x is small compared to ρ_0

➤ Small angle with $p_x / p_s \ll 1$

Longitudinal coordinate:

➤ Longitudinal orbit difference: $l = -v_0 \cdot (t - t_0)$ in unit [mm]

➤ Momentum deviation: $\delta = (p - p_0) / p_0$ sometimes in unit [mrad] = [‰]

For **continuous** beam: l has no meaning \Rightarrow set $l \equiv 0$!

Reference particle: no horizontal and vertical offset $x \equiv y \equiv 0$ and $l \equiv 0$ for all s

Excuse: Definition of Coordinates



The basic vector
is 6 dimensional:

$$\vec{x}(s) = \begin{pmatrix} x \\ x' \\ y \\ y' \\ l \\ \delta \end{pmatrix} = \begin{pmatrix} \text{hori. spatial deviation} \\ \text{horizontal divergence} \\ \text{vert. spatial deviation} \\ \text{vertical divergence} \\ \text{longitudinal deviation} \\ \text{momentum deviation} \end{pmatrix} = \begin{pmatrix} [\text{mm}] \\ [\text{mrad}] \\ [\text{mm}] \\ [\text{mrad}] \\ [\text{mm}] \\ [\text{\%o}] \end{pmatrix}$$

The transformation
from a location s_0 to s_1 is given
by the Transfer Matrix \mathbf{R}

$$\vec{x}(s_1) = \mathbf{R}(s) \cdot \vec{x}(s_0) = \begin{pmatrix} R_{11} & R_{12} & R_{13} & R_{14} & R_{15} & R_{16} \\ R_{21} & R_{22} & R_{23} & R_{24} & R_{25} & R_{26} \\ R_{31} & R_{32} & R_{33} & R_{34} & R_{35} & R_{36} \\ R_{41} & R_{42} & R_{43} & R_{44} & R_{45} & R_{46} \\ R_{51} & R_{52} & R_{53} & R_{54} & R_{55} & R_{56} \\ R_{61} & R_{62} & R_{63} & R_{64} & R_{65} & R_{66} \end{pmatrix} \cdot \begin{pmatrix} x_0 \\ x_0' \\ y_0 \\ y_0' \\ l_0 \\ \delta_0 \end{pmatrix}$$

Remark: At ring accelerator a
comparable (i.e. a bit different)
matrix is called \mathbf{M}

Excuse: Conservation of Emittance



Liouville's Theorem:

The phase space density can not change with conservative e.g. linear forces.

The beam distribution at one location s_0 is described by the beam matrix $\sigma(s_0)$

This beam matrix is transported from location s_0 to s_1 via the transfer matrix

$$\sigma(s_1) = \mathbf{R} \cdot \sigma(s_0) \cdot \mathbf{R}^T$$

6-dim beam matrix with decoupled horizontal and vertical plane:

$$\sigma = \begin{pmatrix} \sigma_{11} & \sigma_{12} & 0 & 0 & \sigma_{15} & \sigma_{16} \\ \sigma_{12} & \sigma_{22} & 0 & 0 & \sigma_{25} & \sigma_{26} \\ 0 & 0 & \sigma_{33} & \sigma_{34} & 0 & 0 \\ 0 & 0 & \sigma_{34} & \sigma_{44} & 0 & 0 \\ \sigma_{15} & \sigma_{25} & 0 & 0 & \sigma_{55} & \sigma_{56} \\ \sigma_{16} & \sigma_{26} & 0 & 0 & \sigma_{56} & \sigma_{66} \end{pmatrix}$$

Horizontal
beam matrix:

$$\sigma_{11} = \langle x^2 \rangle$$

$$\sigma_{12} = \langle x \cdot x' \rangle$$

$$\sigma_{22} = \langle x'^2 \rangle$$

Beam width for
the three coordinates:

$$x_{rms} = \sqrt{\langle x^2 \rangle} = \sqrt{\sigma_{11}}$$

$$y_{rms} = \sqrt{\langle y^2 \rangle} = \sqrt{\sigma_{33}}$$

$$l_{rms} = \sqrt{\langle l^2 \rangle} = \sqrt{\sigma_{55}}$$

Excuse: Some Examples for linear Transformations



The 2-dim sub-space (x, x') can be used in case there is coupling like dispersion $R_{16} = (x / \delta) = 0$

Important examples are:

➤ Drift with length L : $\mathbf{R}_{\text{drift}} = \begin{pmatrix} 1 & L \\ 0 & 1 \end{pmatrix}$

➤ Horizontal **focusing** with quadrupole constant k and effective length l :

$$\mathbf{R}_{\text{focus}} = \begin{pmatrix} \cos \sqrt{k} l & \frac{1}{\sqrt{k}} \sin \sqrt{k} l \\ -\sqrt{k} \cdot \sin \sqrt{k} l & \cos \sqrt{k} l \end{pmatrix} \Rightarrow \mathbf{R}_{\text{focus}}^{\text{thin lens}} = \begin{pmatrix} 1 & 0 \\ -1/f & 1 \end{pmatrix}$$

➤ Horizontal **de-focusing** with quadrupole constant k and effective length l :

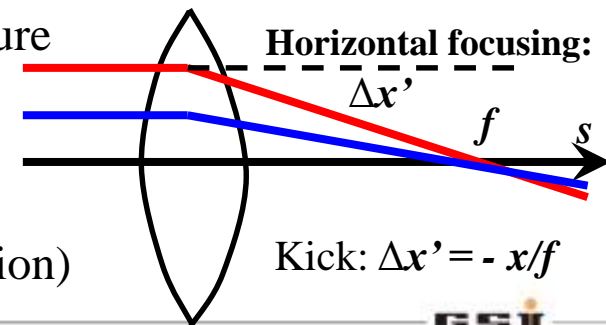
$$\mathbf{R}_{\text{de-focus}} = \begin{pmatrix} \cosh \sqrt{k} l & \frac{1}{\sqrt{k}} \sinh \sqrt{k} l \\ \sqrt{k} \cdot \sinh \sqrt{k} l & \cosh \sqrt{k} l \end{pmatrix} \Rightarrow \mathbf{R}_{\text{de-focus}}^{\text{thin lens}} = \begin{pmatrix} 1 & 0 \\ 1/f & 1 \end{pmatrix}$$

Ideal quad.: field gradient $g = B_{\text{pole}}/a$, B_{pole} field at poles, a aperture

→ quadrupole constant $k = |g| / (B\rho)_0$

Thin lens approximation: $l \rightarrow 0 \Rightarrow kl \rightarrow \text{const} \Rightarrow kl \equiv 1/f$

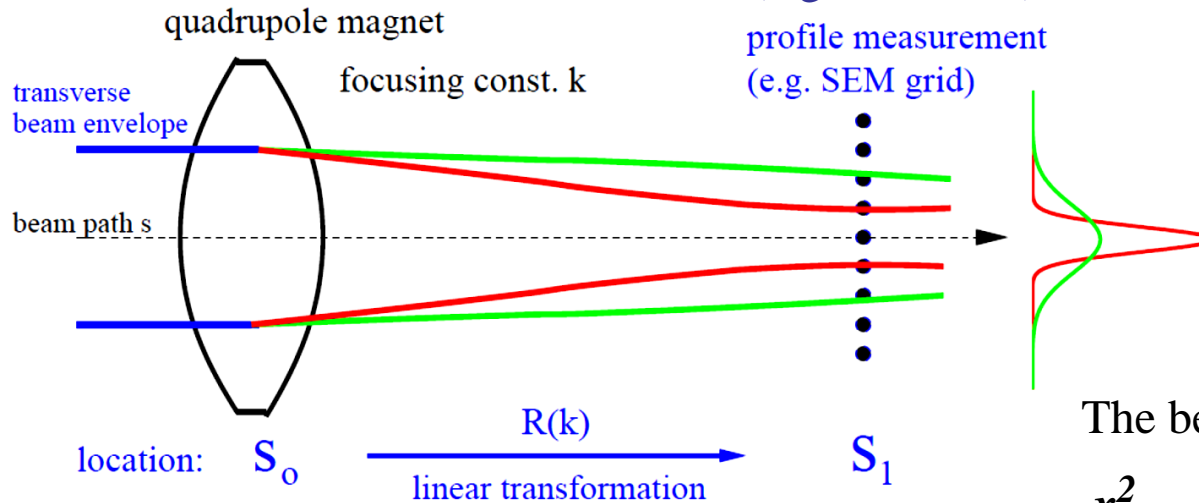
⇒ simple transfer matrix (math. proof by 1st order Taylor expansion)



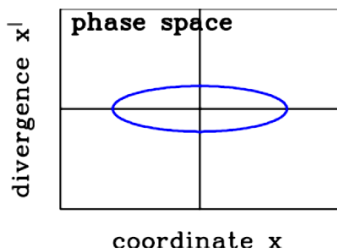
Emittance Measurement by Quadrupole Variation



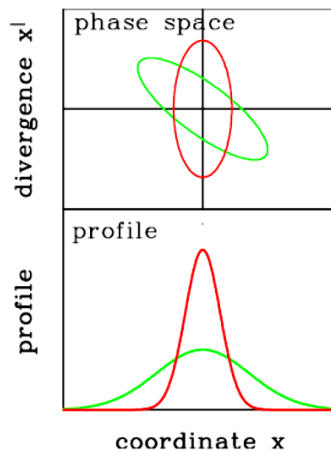
From a profile determination, the emittance can be calculated via linear transformation, if a well known and constant distribution (e.g. Gaussian) is assumed.



The beam width x_{max} and $x_{max}^2 = \sigma_{11}(l, k)$ is measured, matrix $\mathbf{R}(\mathbf{k})$ describes the focusing.



beam matrix:
(Twiss parameters)
 $\sigma_{11}(0), \sigma_{12}(0), \sigma_{22}(0)$
to be determined



measurement:
 $x^2(k) = \sigma_{11}(l, k)$

Measurement of transverse Emittance



- The beam width x_{max} at s_1 is measured, and therefore $\sigma_{11}(1, k_i) = x_{max}^2(k_i)$.
- Different focusing of the quadrupole $k_1, k_2 \dots k_n$ is used: $\Rightarrow \mathbf{R}_{\text{focus}}(k_i)$, including the drift, the transfer matrix is changed $\mathbf{R}(k_i) = \mathbf{R}_{\text{drift}} \cdot \mathbf{R}_{\text{focus}}(k_i)$.
- Task: Calculation of *beam* matrix $\sigma(0)$ at entrance s_0 (size and orientation of ellipse)
- The transformations of the beam matrix are: $\sigma(1, k) = \mathbf{R}(k) \cdot \sigma(0) \cdot \mathbf{R}^T(k)$.
 \Rightarrow Resulting in a redundant system of linear equations for $\sigma_{ij}(0)$:

$$\begin{aligned} \sigma_{11}(1, k_1) &= R_{11}^2(k_1) \cdot \sigma_{11}(0) + 2R_{11}(k_1)R_{12}(k_1) \cdot \sigma_{12}(0) + R_{12}^2(k_1) \cdot \sigma_{22}(0) \quad \text{focusing } k_1 \\ &\vdots \\ \sigma_{11}(1, k_n) &= R_{11}^2(k_n) \cdot \sigma_{11}(0) + 2R_{11}(k_n)R_{12}(k_n) \cdot \sigma_{12}(0) + R_{12}^2(k_n) \cdot \sigma_{22}(0) \quad \text{focusing } k_n \end{aligned}$$

- To learn something on possible errors, $n > 3$ settings have to be performed.
A setting with a focus close to the SEM-grid should be included to do a good fit.
- *Assumptions:*
 - Only elliptical shaped emittance can be obtained.
 - No broadening of the emittance e.g. due to space-charge forces.
 - If *not* valid: A self-consistent algorithm has to be used.

Measurement of transverse Emittance



Using the 'thin lens approximation' i.e. the quadrupole has a focal length of f :

$$\mathbf{R}_{focus}(K) = \begin{pmatrix} 1 & 0 \\ -1/f & 1 \end{pmatrix} \equiv \begin{pmatrix} 1 & 0 \\ K & 1 \end{pmatrix} \Rightarrow \mathbf{R}(L, K) = \mathbf{R}_{drift}(L) \cdot \mathbf{R}_{focus}(K) = \begin{pmatrix} 1+LK & L \\ K & 1 \end{pmatrix}$$

Example: Square of the beam width at ELETTRA 100 MeV e^- Linac, YAG:Ce:

$$\text{Measurement of } \sigma(1, K) = \mathbf{R}(K) \cdot \sigma(0) \cdot \mathbf{R}^T(K)$$

$$\sigma_{11}(1, K) = L^2 \sigma_{11}(0) \cdot K^2$$

$$+ 2 \cdot (L \sigma_{11}(0) + L^2 \sigma_{12}(0)) \cdot K$$

$$+ L^2 \sigma_{22}(0) + \sigma_{11}(0)$$

$$\equiv a \cdot K^2 - 2ab \cdot K + ab^2 + c$$

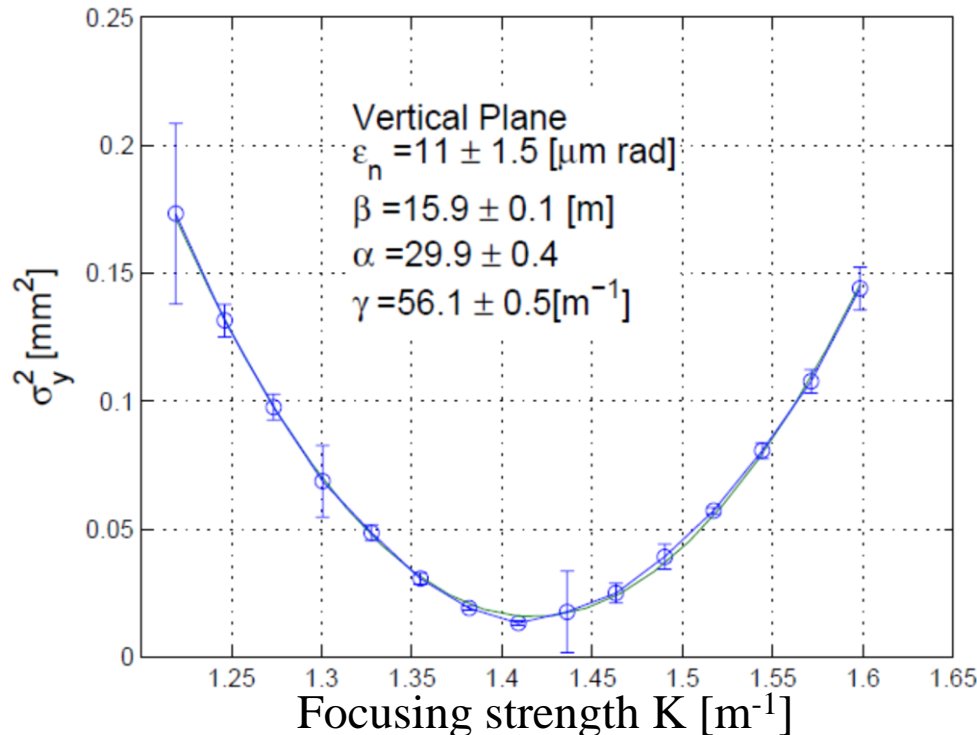
The σ -matrix at quadrupole is:

$$\sigma_{11}(0) = \frac{a}{L^2}$$

$$\sigma_{12}(0) = -\frac{a}{L^2} \left(\frac{1}{L} + b \right)$$

$$\sigma_{22}(0) = \frac{1}{L^2} \left(ab^2 + c + \frac{2ab}{L} + \frac{a}{L^2} \right)$$

$$\epsilon = \sqrt{\det \sigma(0)} = \sqrt{\sigma_{11}(0)\sigma_{22}(0) - \sigma_{12}^2(0)} = \sqrt{ac}/L^2$$



G. Penco et al., EPAC'08

The 'Three Grid Method' for Emittance Measurement



Instead of quadrupole variation, the beam width is measured at *different* locations:

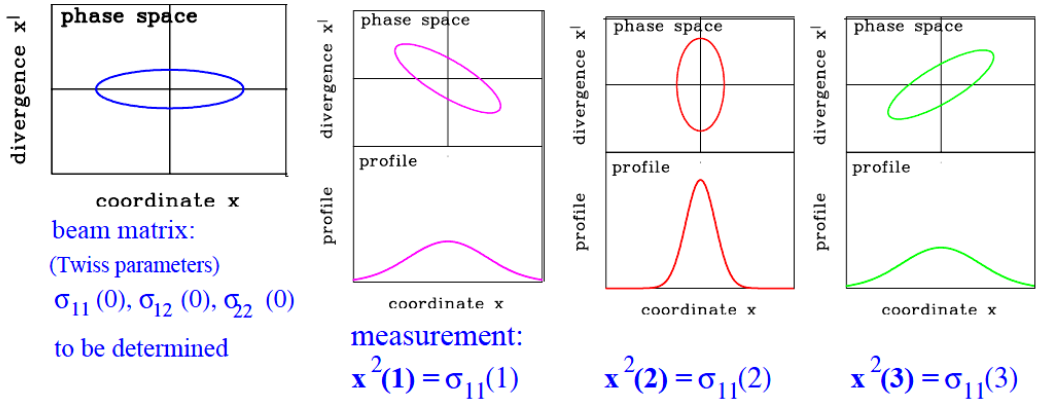
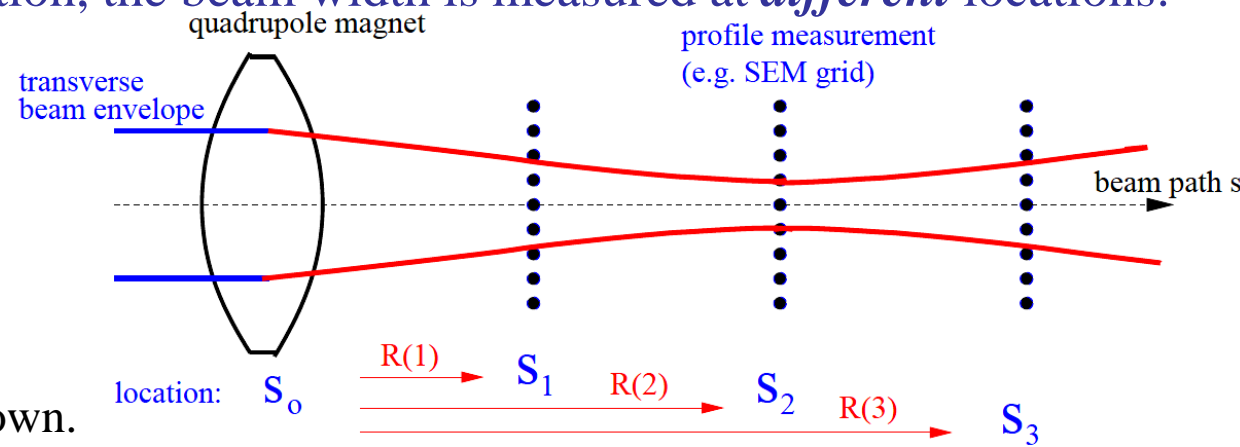
The procedure is:

- Beam width $x(i)$ measured at the locations s_i
 ⇒ beam matrix element $x^2(i) = \sigma_{11}(i)$.

- The transfer matrix $\mathbf{R}(i)$ is known.
 (without dipole a 3×3 matrix.)

- The transformations are:
 $\sigma(i) = \mathbf{R}(i)\sigma(0)\mathbf{R}^T(i)$

⇒ redundant equations:



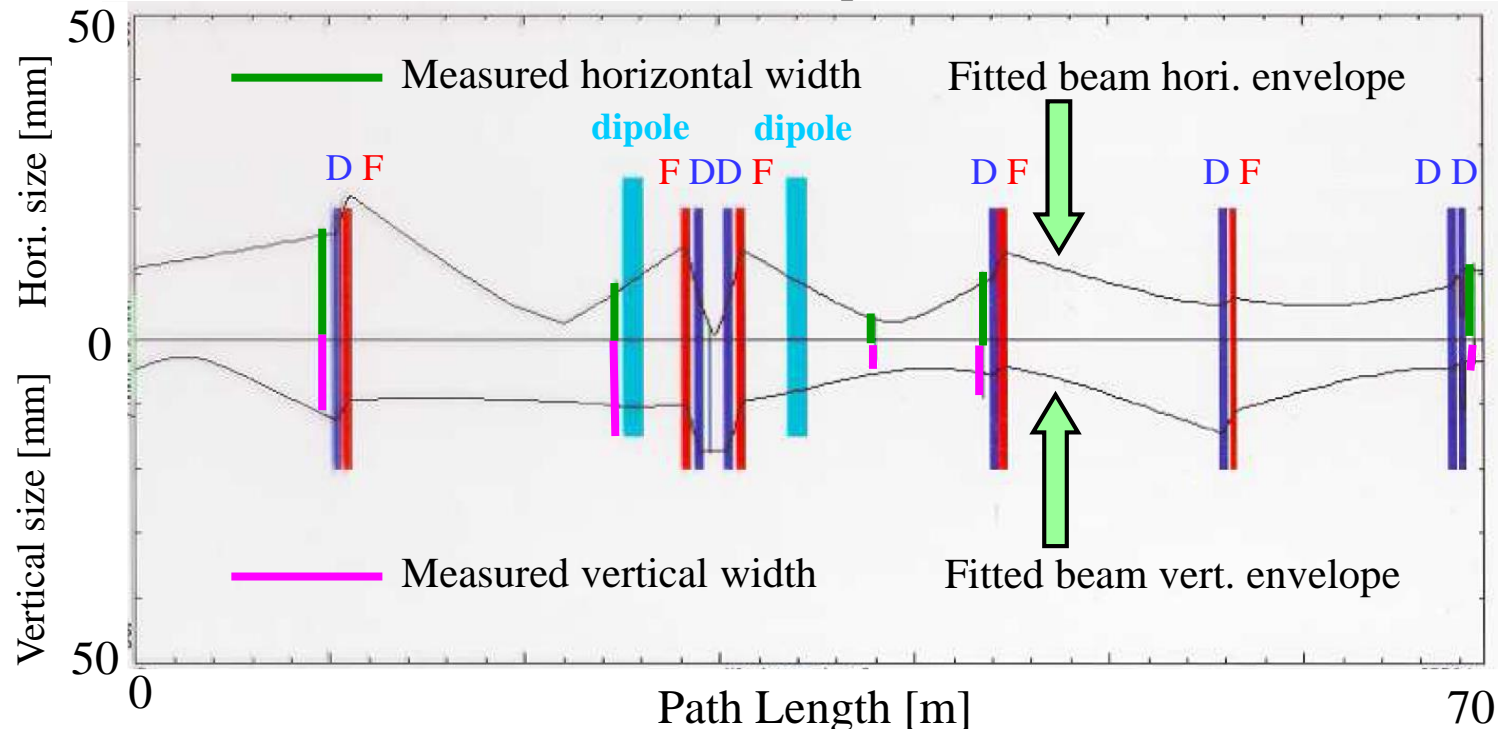
$$\begin{aligned} \sigma_{11}(1) &= R_{11}^2(1) \cdot \sigma_{11}(0) + 2R_{11}(1)R_{12}(1) \cdot \sigma_{12}(0) + R_{12}^2(1) \cdot \sigma_{22}(0) & \mathbf{R}(1) : s_0 \rightarrow s_1 \\ \sigma_{11}(2) &= R_{11}^2(2) \cdot \sigma_{11}(0) + 2R_{11}(2)R_{12}(2) \cdot \sigma_{12}(0) + R_{12}^2(2) \cdot \sigma_{22}(0) & \mathbf{R}(2) : s_0 \rightarrow s_2 \\ &\vdots \\ \sigma_{11}(n) &= R_{11}^2(n) \cdot \sigma_{11}(0) + 2R_{11}(n)R_{12}(n) \cdot \sigma_{12}(0) + R_{12}^2(n) \cdot \sigma_{22}(0) & \mathbf{R}(n) : s_0 \rightarrow s_n \end{aligned}$$

Results of a 'Three Grid Method' Measurement



Solution: Solving the linear equations like for quadrupole variation or fitting the profiles with linear optics code (e.g. TRANSPORT, WinAgile, MadX).

Example: The hor. and vert. beam envelope and the beam width at a transfer line:



- Assumptions:**
- constant emittance, in particular no space-charge broadening
 - 100 % transmission i.e. no loss due to vacuum pipe scraping
 - no misalignment, i.e. beam center equals center of the quadrupoles.

Summary for transverse Emittance Measurement



Emittance measurements are very important for comparison to theory.

It includes size (value of ϵ) and orientation in phase space (σ_{ij} or α , β and γ)

(three independent values)

Techniques for transfer lines (synchrotron: width measurement sufficient):

Low energy beams → direct measurement of x - and x' -distribution

➤ ***Slit-grid***: movable slit → x -profile, grid → x' -profile

➤ ***Pepper-pot***: holes → x -profile, scintillation screen → x' -profile

All beams → profile measurement + linear transformation:

➤ ***Quadrupole variation***: one location, different setting of a quadrupole

➤ ***'Three grid method'***: different locations

➤ ***Assumptions***: ➤ well aligned beam, no steering

➤ no emittance blow-up due to space charge.

Appendix GSI Ion LINAC: Emittance Measurement Devices



Slit Grid Emittance: Standard device, total 9 device



Pepper-pot Emittance: Special device, total 1 device

Transfer to
Synchrotron

